

**April 2013** 

## FDD5N50NZF

# N-Channel UniFET<sup>TM</sup> FRFET<sup>®</sup> MOSFET 500 V, 3.7 A, 1.75 $\Omega$

#### **Features**

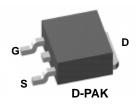
- $R_{DS(on)} = 1.47 \Omega \text{ (Typ.)} @ V_{GS} = 10 \text{ V}, I_D = 1.85 \text{ A}$
- Low Gate Charge (Typ. 9n C)
- Low C<sub>rss</sub> (Typ. 4 pF)
- 100% Avalanche Tested
- · Improved dv/dt Capability
- · ESD Imoroved Capability
- RoHS Compliant

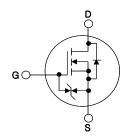
## **Applications**

- LCD/LED/PDP TV
- Lighting
- · Uninterruptible Power Supply

## **Description**

UniFETTM II MOSFET is Fairchild Semiconductor®'s high voltage MOSFET family based on advanced planar stripe and DMOS technology. This advanced MOSFET family has the smallest on-state resistance among the planar MOSFET, and also provides superior switching performance and higher avalanche energy strength. In addition, internal gate-source ESD diode allows UniFET II MOSFET to withstand over 2kV HBM surge stress. The body diode's reverse recovery performance of UniFET II FRFET® MOSFET has been enhanced by lifetime control. Its  $t_{rr}$  is less than 100nsec and the reverse dv/dt immunity is 15V/ns while normal planar MOSFETs have over 200nsec and 4.5V/nsec respectively. Therefore, it can remove additional component and improve system reliability in certain applications in which the performance of MOSFET's body diode is significant. This device family is suitable for switching power converter applications such as power factor correction (PFC), flat panel display (FPD) TV power, ATX and electronic lamp ballasts.





## MUSFEI Maximum Katings T<sub>C</sub> = 25°C unless otherwise noted\*

Symbol		Parameter		FDD5N50NZF	Unit
V <sub>DSS</sub>	Drain to Source Voltage			500	V
V <sub>GSS</sub>	Gate to Source Voltage			±25	V
	Drain Current	- Continuous (T <sub>C</sub> = 25°C)		3.7	۸
I <sub>D</sub>	Diain Current	- Continuous (T <sub>C</sub> = 100°C)		2.2	Α
I <sub>DM</sub>	Drain Current	- Pulsed	(Note 1)	14	Α
E <sub>AS</sub>	Single Pulsed Avalanche En	ergy	(Note 2)	165	mJ
I <sub>AR</sub>	Avalanche Current		(Note 1)	3.3	Α
E <sub>AR</sub>	Repetitive Avalanche Energy	у	(Note 1)	6.25	mJ
dv/dt	Peak Diode Recovery dv/dt		(Note 3)	20	V/ns
D	Dower Dissination	$(T_C = 25^{\circ}C)$		62.5	W
$P_{D}$	Power Dissipation	- Derate above 25°C		0.5	W/ºC
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temp	perature Range		-55 to +150	οС
T <sub>L</sub>	Maximum Lead Temperature 1/8" from Case for 5 Second	• •		300	°C

Drain current limited by maximum junction temperature

#### **Thermal Characteristics**

Symbol	Parameter	FDD5N50NZF	Unit	
$R_{ heta JC}$	Thermal Resistance, Junction to Case, Max.	2 °C/\		
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient, Max.	62.5	C/VV	

## **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD5N50NZF	FDD5N50NZFTM	D-PAK	380mm	16mm	2500

## **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min.	Тур.	Max.	Unit
Off Charac	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A$ , $V_{GS} = 0 V$ , $T_C = 25 ^{\circ} C$	500	-	-	V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	$I_D = 250\mu\text{A}$ , Referenced to $25^{\circ}\text{C}$	-	0.5	-	V/°C
ı	Zoro Coto Voltago Proin Current	$V_{DS} = 500V, V_{GS} = 0V$	-	-	10	^
IDSS	Zero Gate Voltage Drain Current	$V_{DS} = 400V, V_{GS} = 0V, T_{C} = 125^{\circ}C$	-	-	100	μΑ
I <sub>GSS</sub>	Gate to Body Leakage Current	$V_{GS} = \pm 25V, V_{DS} = 0V$	-	-	±10	μА

#### **On Characteristics**

$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 250\mu A$	3.0	-	5.0	V
R <sub>DS(on)</sub>	Static Drain to Source On Resistance	$V_{GS} = 10V, I_D = 1.85A$	-	1.47	1.75	Ω
g <sub>FS</sub>	Forward Transconductance	$V_{DS} = 20V, I_{D} = 1.85A$	-	4.2	-	S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> = 25V, V <sub>GS</sub> = 0V		365	485	pF
Coss	Output Capacitance			50	65	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 11/11/2	-	4	8	pF
Q <sub>g(tot)</sub>	Total Gate Charge at 10V		-	9	12	nC
Q <sub>gs</sub>	Gate to Source Gate Charge	$V_{DS} = 400 V I_{D} = 3.7 A$	-	2	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge	V <sub>GS</sub> = 10V (Not	e 4) -	4	-	nC

## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time		-	12	35	ns
t <sub>r</sub>	Turn-On Rise Time	$V_{DD} = 250V, I_D = 3.7A$	-	19	50	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$V_{GS} = 10V$ , $R_{GEN} = 25\Omega$	-	31	70	ns
t <sub>f</sub>	Turn-Off Fall Time	(Note 4)	-	22	55	ns

#### **Drain-Source Diode Characteristics**

I <sub>S</sub>	Maximum Continuous Drain to Source Diode Forward Current		-		3.7	Α
I <sub>SM</sub>	Maximum Pulsed Drain to Source Diode Forward Current		-	-	14	Α
$V_{SD}$	Drain to Source Diode Forward Voltage V <sub>GS</sub> = 0V, I <sub>SD</sub> = 3.7A		-	-	1.5	V
t <sub>rr</sub>	Reverse Recovery Time	$V_{GS} = 0V, I_{SD} = 3.7A$	-	87	-	ns
Q <sub>rr</sub>	Reverse Recovery Charge $dI_F/dt = 100A/\mu s$		-	0.15	-	μС

#### Notes

- Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. L = 23mH, I  $_{AS}$  = 3.7A, V  $_{DD}$  = 50V, R  $_{G}$  = 25 $\Omega$ , Starting T  $_{J}$  = 25 $^{\circ}C$
- 3.  $I_{SD} \leq$  3.7A, di/dt  $\leq$  200A/ $\mu$ s,  $V_{DD} \leq$  BV $_{DSS}$ , Starting  $T_J$  = 25°C
- 4. Essentially Independent of Operating Temperature Typical Characteristics

## **Typical Performance Characteristics**

Figure 1. On-Region Characteristics

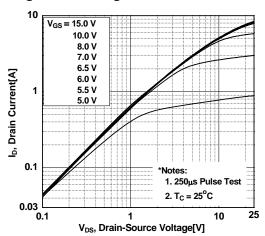


Figure 3. On-Resistance Variation vs.
Drain Current and Gate Voltage

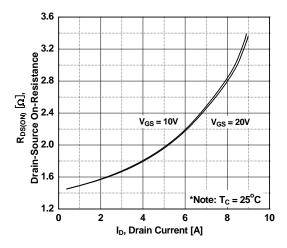


Figure 5. Capacitance Characteristics

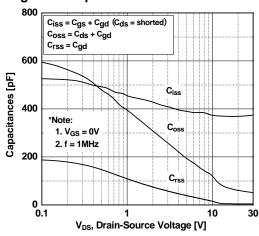


Figure 2. Transfer Characteristics

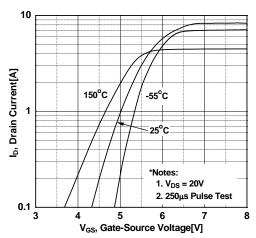


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

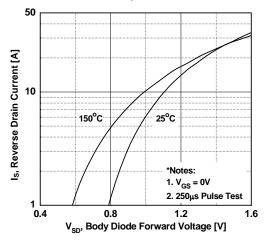
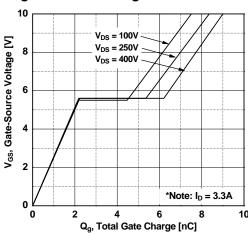


Figure 6. Gate Charge Characteristics



## **Typical Performance Characteristics (Continued)**

Figure 7. Breakdown Voltage Variation vs. Temperature

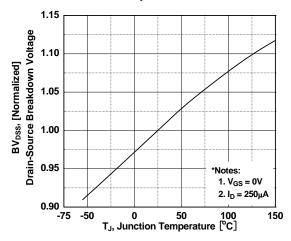


Figure 8. Maximum Safe Operating Area vs. Case Temperature

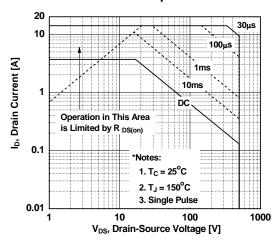


Figure 9. Maximum Drain Current

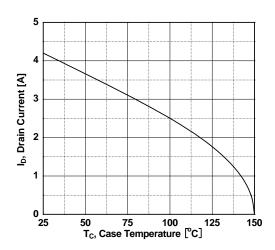
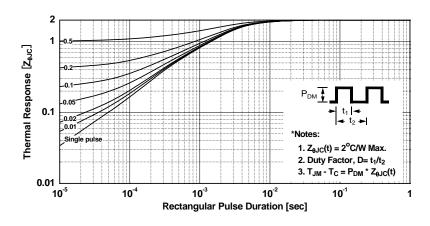
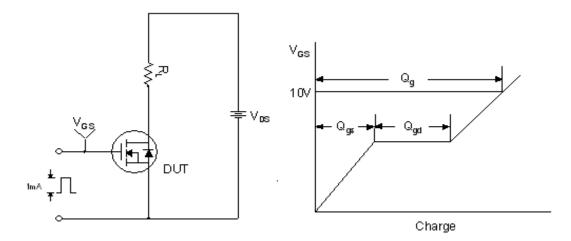


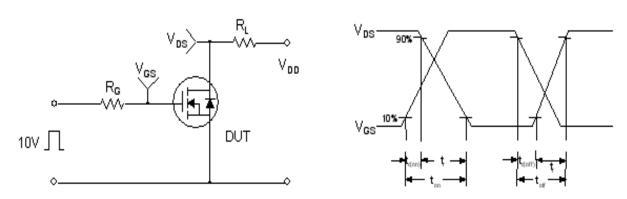
Figure 10. Transient Thermal Response Curve



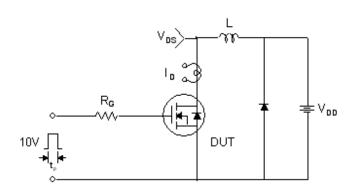
## **Gate Charge Test Circuit & Waveform**

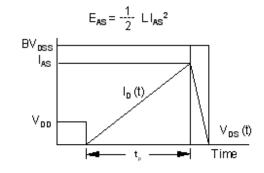


## **Resistive Switching Test Circuit & Waveforms**

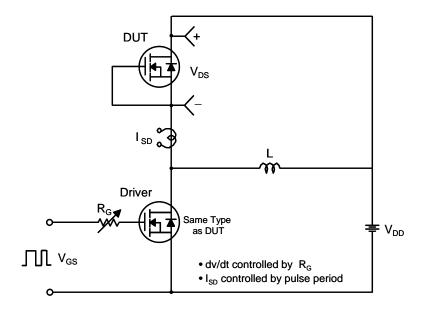


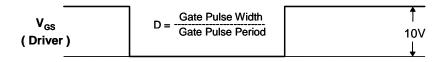
**Unclamped Inductive Switching Test Circuit & Waveforms** 

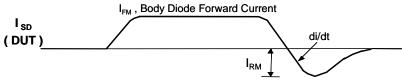




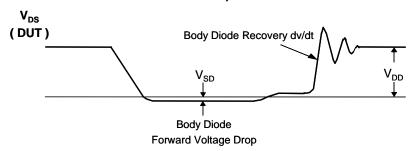
#### Peak Diode Recovery dv/dt Test Circuit & Waveforms





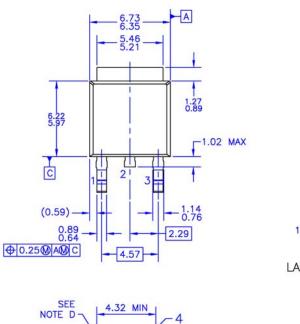


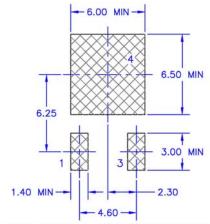
Body Diode Reverse Current

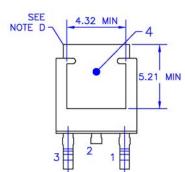


## **Mechanical Dimensions**

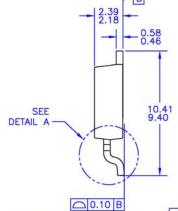
## **D-PAK**











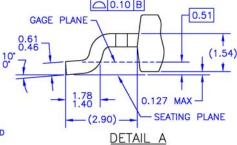
- NOTES: UNLESS OTHERWISE SPECIFIED

  A) THIS PACKAGE CONFORMS TO JEDEC, TO-252, ISSUE C, VARIATION AA.

  B) ALL DIMENSIONS ARE IN MILLIMETERS.
  C) DIMENSIONING AND TOLERANCING PER ASME Y14.5M-1994.

  D) HEAT SINK TOP EDGE COULD BE IN CHAMFERED CORNERS OR EDGE PROTRUSION.
  E) PRESENCE OF TRIMMED CENTER LEAD IS OPTIONAL.

  - IS OPTIONAL.
  - F)
  - DIMENSIONS ARE EXCLUSSIVE OF BURSS, MOLD FLASH AND TIE BAR EXTRUSIONS.
  - LAND PATTERN RECOMENDATION IS BASED ON IPC7351A STD T0220P1003X238-3N.
  - DRAWING NUMBER AND REVISION: MKT-T0252A03REV8



(ROTATED -90°) SCALE: 12X

**Dimensions in Millimeters** 





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No Identification Needed	Full Production	Datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice to improve the design.
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